

TENTATIVE

TOSHIBA CCD LINEAR IMAGE SENSOR CCD (Charge Coupled Device)

TCD1209D

The TCD1209D is a high speed and low dark current 2048 elements CCD image sensor.

The sensor is designed for facsimile, imagescanner and OCR.

The device contains a row of 2048 elements photodiodes which provide a 8 lines/mm (200 DPI) across a B4 size paper. The device is operated by 5 V (pulse), and 12 V power supply.

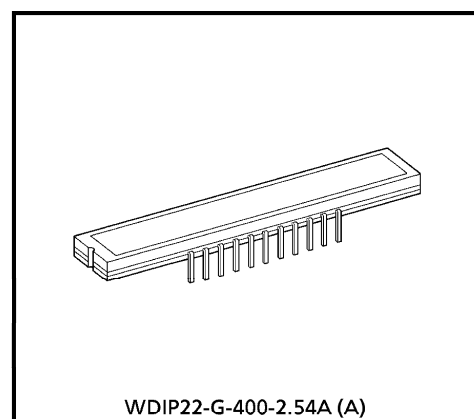
FEATURES

- Number of Image Sensing Elements : 2048 elements
- Image Sensing Element Size
: 14 μm by 14 μm on 14 μm centers
- Photo Sensing Region : High sensitive and low voltage dark signal pn photodiode
- Clock : 2 phase (5 V)
- Package : 22pin Cerdip

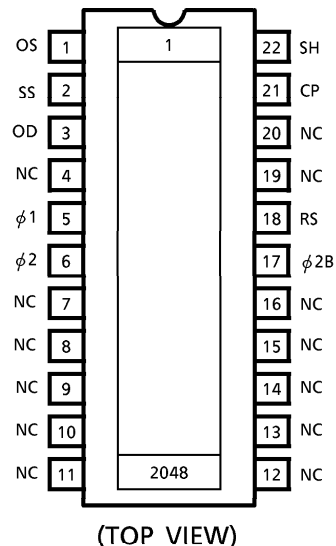
MAXIMUM RATINGS (Note 1)

| CHARACTERISTIC | SYMBOL | RATING | UNIT |
|-----------------------|------------|----------|--------------------|
| Clock Pulse Voltage | V_{ϕ} | - 0.3~8 | V |
| Shift Pulse Voltage | V_{SH} | | |
| Reset Pulse Voltage | V_{RS} | | |
| Clamp Pulse Voltage | V_{CP} | | |
| Power Supply Voltage | V_{OD} | - 0.3~15 | |
| Operating Temperature | T_{opr} | - 25~60 | $^{\circ}\text{C}$ |
| Storage Temperature | T_{stg} | - 40~100 | $^{\circ}\text{C}$ |

(Note 1) All voltage are with respect to SS terminals (Ground).



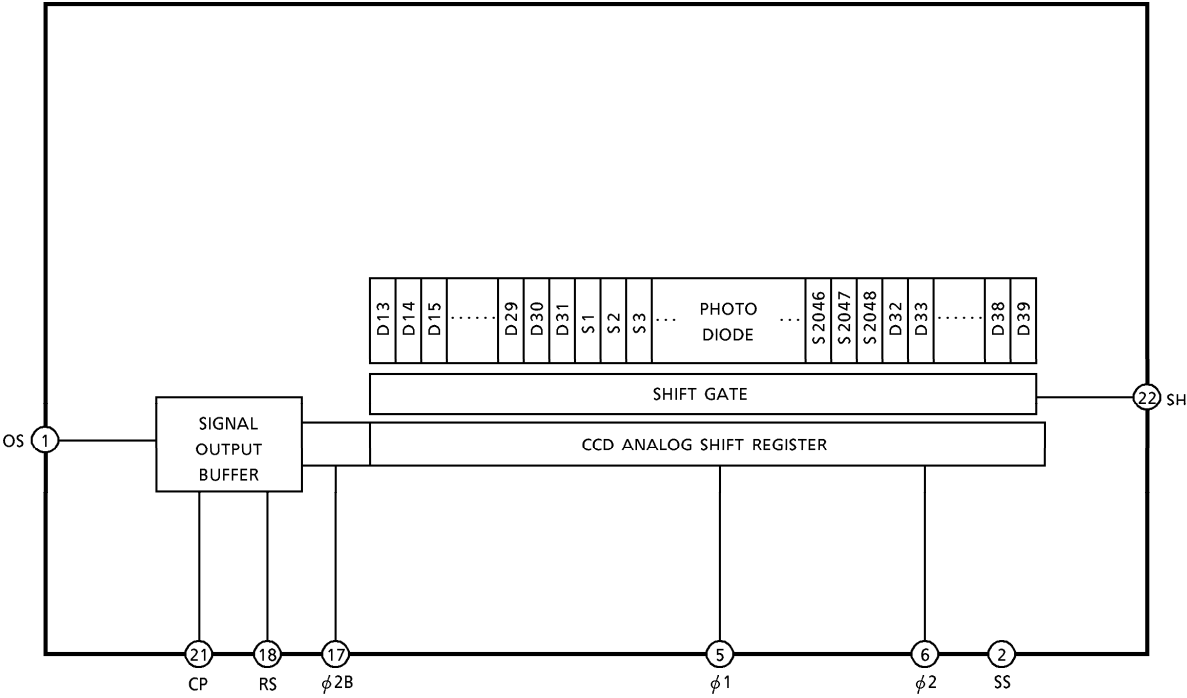
PIN CONNECTIONS



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CIRCUIT DIAGRAM



PIN NAME

| | |
|-----------|-----------------------------|
| $\phi 1$ | Clock (Phase 1) |
| $\phi 2$ | Clock (Phase 2) |
| $\phi 2B$ | Final Stage Clock (Phase 2) |
| SH | Shift Gate |
| RS | Reset Gate |
| CP | Clamp Gate |
| OS | Signal Output |
| OD | Power |
| SS | Ground |
| NC | Non Connection |

OPTICAL / ELECTRICAL CHARACTERISTICS

(Ta = 25°C, V_{OD} = 12 V, V_φ = V_{SH} = V_{RS} = V_{CP} = 5 V (PULSE), f_φ = 1 MHz,
t_{INT} (INTEGRATION TIME) = 10 ms, LIGHT SOURCE = DAYLIGHT FLUORESCENT LAMP,
LOAD RESISTANCE = 100 kΩ)

| CHARACTERISTIC | SYMBOL | MIN. | TYP. | MAX. | UNIT | NOTE |
|-------------------------------|------------------|------|------|------|----------|----------|
| Sensitivity | R | 25 | 31 | 37 | V / lx·s | |
| Photo Response Non Uniformity | PRNU | — | 3 | 10 | % | (Note 2) |
| | PRNU (3) | — | 4 | 10 | mV | (Note 8) |
| Saturation Output Voltage | V _{SAT} | 1.5 | 2.0 | — | V | (Note 3) |
| Saturation Exposure | SE | 0.04 | 0.06 | — | lx·s | (Note 4) |
| Dark Signal Voltage | V _{DRK} | — | 1.0 | 2.5 | mV | (Note 5) |
| Dark Signal Non Uniformity | DSNU | — | 1.0 | 2.5 | mV | (Note 5) |
| DC Power Dissipation | P _D | — | 160 | 400 | mW | |
| Total Transfer Efficiency | TTE | 92 | 98 | — | % | |
| Output Impedance | Z _O | — | 0.2 | 1 | kΩ | |
| Dynamic Range | DR | — | 2000 | — | — | (Note 6) |
| DC Signal Output Voltage | V _{OS} | 4.0 | 5.5 | 7.0 | V | (Note 7) |
| Random Noise | ND _σ | — | 0.6 | — | mV | (Note 9) |

(Note 2) Measured at 50% of SE (Typ.)

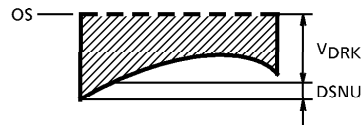
$$\text{Definition of PRNU : PRNU} = \frac{\Delta \bar{x}}{\bar{x}} \times 100 (\%)$$

Where \bar{x} is average of total signal outputs and $\Delta \bar{x}$ is maximum deviation from \bar{x} under uniform illumination.

(Note 3) V_{SAT} is defined as minimum saturation output voltage of all effective pixels.

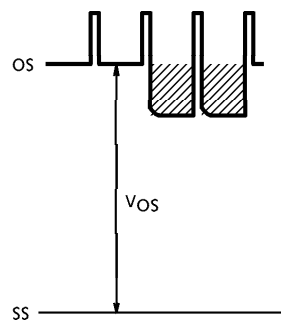
$$\text{(Note 4) Definition of SE : SE} = \frac{V_{SAT}}{R} \text{ (lx·s)}$$

- (Note 5) V_{DRK} is defined as average dark signal voltage of all effective pixels.
 $DSNU$ is defined as different voltage between V_{DRK} and V_{MDK} when V_{MDK} is maximum dark signal voltage.



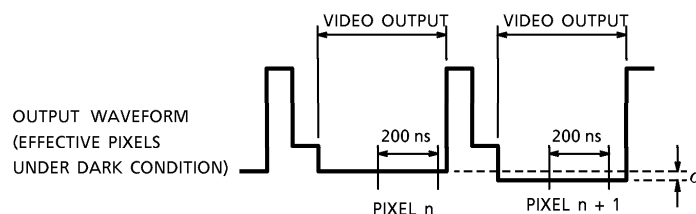
- (Note 6) Definition of DR : $DR = \frac{V_{SAT}}{V_{DRK}}$
 V_{DRK} is proportional to t_{INT} (Integration Time).
 So the shorter t_{INT} condition makes wider DR values.

- (Note 7) DC signal output voltage and DC compensation output voltage are defined as follows:



- (Note 8) PRNU (3) is defined as maximum voltage with next pixel, where measured 5% of SE (Typ.)

(Note 9) Random noise is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e. dark condition) calculated by the following procedure.



- 1) Two adjacent pixels (pixel n and n + 1) in one reading are fixed as measurement points.
- 2) Each of the output levels at video output periods averaged over 200 nanosecond period to get V_n and V_{n+1} .
- 3) V_{n+1} is subtracted from V_n to get ΔV .

$$\Delta V = V_n - V_{n+1}$$
- 4) The standard deviation of ΔV is calculated after procedure 2) and 3) are repeated 30 times (30 readings).

$$\overline{\Delta V} = \frac{1}{30} \sum_{i=1}^{30} |\Delta V_i| \quad \sigma = \sqrt{\frac{1}{30} \sum_{i=1}^{30} (|\Delta V_i| - \overline{\Delta V})^2}$$

- 5) Procedure 2), 3) and 4) are repeated 10 times to get 10 sigma values.

$$\overline{\sigma} = \frac{1}{10} \sum_{j=1}^{10} \sigma_j$$

- 6) $\overline{\sigma}$ value calculated using the above procedure is observed $\sqrt{2}$ times larger than that measured relative to the ground level. So we specify the random noise as follows.

$$\text{Random noise} = \frac{1}{\sqrt{2}} \overline{\sigma}$$

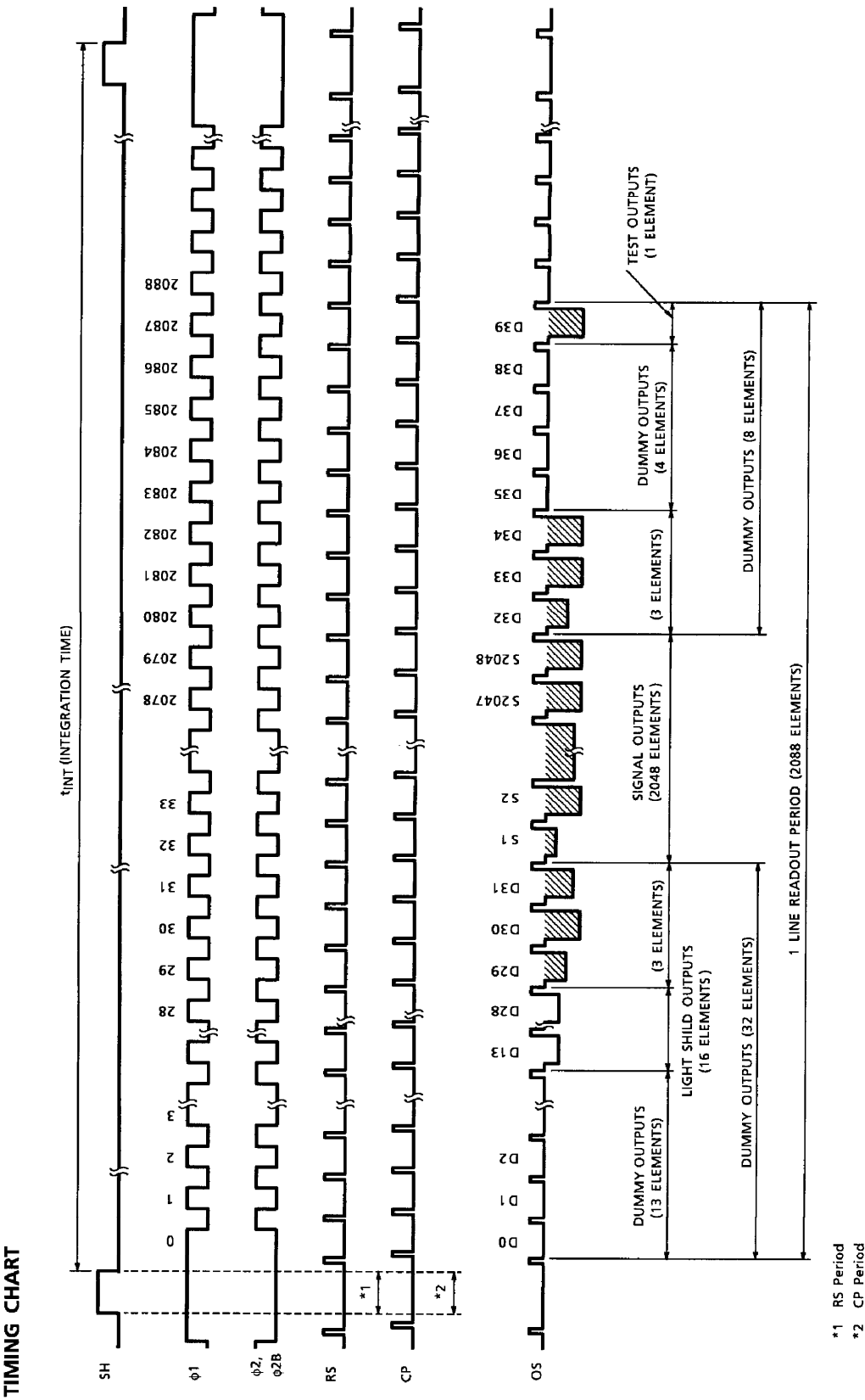
OPERATING CONDITION

| CHARACTERISTIC | | SYMBOL | MIN. | TYP. | MAX. | UNIT |
|---------------------------|-----------|---------------|------|------|------|------|
| Clock Pulse Voltage | "H" Level | $V_{\phi 1}$ | 4.5 | 5 | 5.5 | V |
| | "L" Level | $V_{\phi 2}$ | 0 | — | 0.5 | |
| Final Stage Clock Voltage | "H" Level | $V_{\phi 2B}$ | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Shift Pulse Voltage | "H" Level | V_{SH} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Reset Pulse Voltage | "H" Level | V_{RS} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Clamp Pulse Voltage | "H" Level | V_{CP} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Power Supply Voltage | | V_{OD} | 11.4 | 12.0 | 13.0 | V |

CLOCK CHARACTERISTICS (Ta = 25°C)

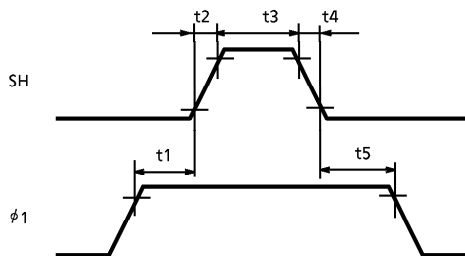
| CHARACTERISTIC | | SYMBOL | MIN. | TYP. | MAX. | UNIT |
|-------------------------------|--|--------------|------|------|------|------|
| Clock Pulse Frequency | | f_{ϕ} | — | 1 | 20 | MHz |
| Reset Pulse Frequency | | f_{RS} | — | 1 | 20 | MHz |
| Clock Capacitance (Note 10) | | $C_{\phi 1}$ | — | 200 | — | pF |
| | | $C_{\phi 2}$ | — | 200 | — | |
| Final Stage Clock Capacitance | | $C_{\phi B}$ | — | 10 | 20 | pF |
| Shift Gate Capacitance | | C_{SH} | — | 30 | — | pF |
| Reset Gate Capacitance | | C_{RS} | — | 10 | 20 | pF |
| Clamp Gate Capacitance | | C_{CP} | — | 10 | 20 | pF |

(Note 10) $V_{OD} = 12\text{ V}$

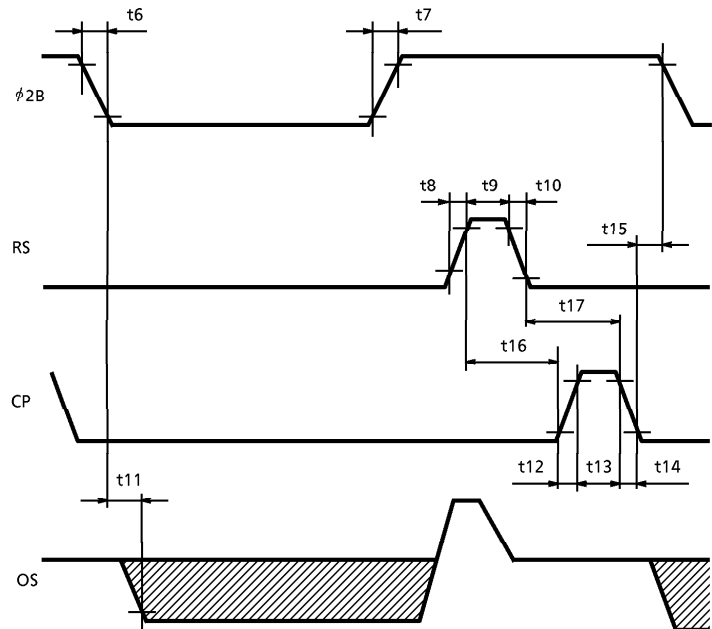


TIMING REQUIREMENTS

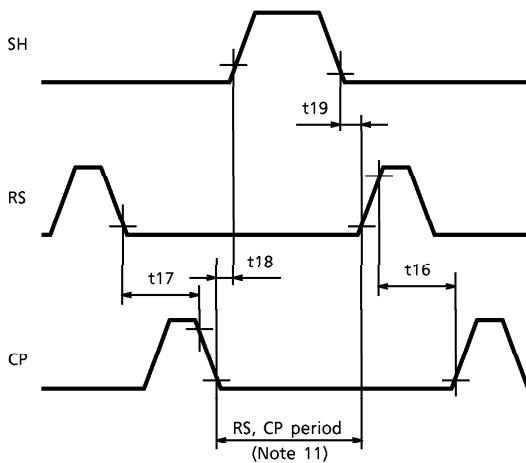
SH, $\phi 1$ Timing



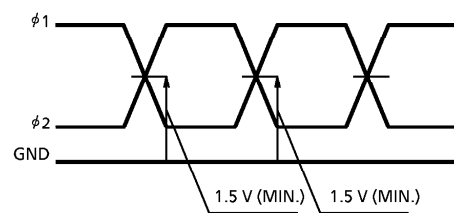
$\phi 2$, RS, CP, OS Timing



SH, RS, CP Timing



$\phi 1$, $\phi 2$ CROSS POINT



(Note 11) Each RS and CP pins put to Low level during this period.

| CHARACTERISTIC | SYMBOL | MIN. | TYP. (Note 12) | MAX. | UNIT |
|--------------------------------------|----------|------|-------------------|------|------|
| Pulse Timing of SH and $\phi 1$ | t1, t5 | 200 | 500 | — | ns |
| SH Pulse Rise Time, Fall Time | t2, t4 | 0 | 50 | — | ns |
| SH Pulse Width | t3 | 1000 | 1500 | — | ns |
| $\phi 2B$ Pulse Rise Time, Fall Time | t6, t7 | 0 | 100 | — | ns |
| RS Pulse Rise Time, Fall Time | t8, t10 | 0 | 20 | — | ns |
| RS Pulse Width | t9 | 10 | 100 | — | ns |
| Video Data Delay Time (Note 13) | t11 | — | 15 | — | ns |
| CP Pulse Rise Time, Fall Time | t12, t14 | 0 | 20 | — | ns |
| CP Pulse Width | t13 | 10 | 100 | — | ns |
| Pulse Timing of $\phi 2B$ and CP | t15 | 0 | 50 | — | ns |
| Pulse Timing of RS and CP | t16 | 0 | 100 | — | ns |
| | t17 | 10 | 100 | — | |
| Pulse Timing of SH and CP | t18 | 200 | — | — | ns |
| Pulse Timing of SH and RS | t19 | 200 | — | — | ns |

(Note 12) TYP. is the case of $f_{RS} = 1.0 \text{ MHz}$

(Note 13) Load Resistance is $100 \text{ k}\Omega$

PRECAUTIONS FOR USE OF CCD IMAGE SENSOR**1. Static Electricity**

This device has some weakly terminals for static electricity. Therefore, please pay attention to treat this device.

CCD Image Sensor is protected against static electricity, but inferior puncture mode device due to static electricity is sometimes detected. In handling the device, it is necessary to execute the following static electricity preventive measures, in order to prevent the trouble rate increase of the manufacturing system due to static electricity.

- a. Prevent the generation of static electricity due to friction by making the work with bare hands or by putting on cotton gloves and non-charging working clothes.
- b. Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work room.
- c. Ground the tools such as soldering iron, radio cutting plier or pincette.

It is not necessarily required to execute all precaution items for static electricity.

It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

2 Window Glass

As the dust and station on the glass window of the package will cause black flow on the picture, never fail to clean the glass surface before using. (Blow compressed vapor, and wipe off the dust, and dirt with soft cloth or paper slightly moistened with alcohol).

Fully take care for the handling of the device as the window glass will break or a strong friction is given to the window glass surface.

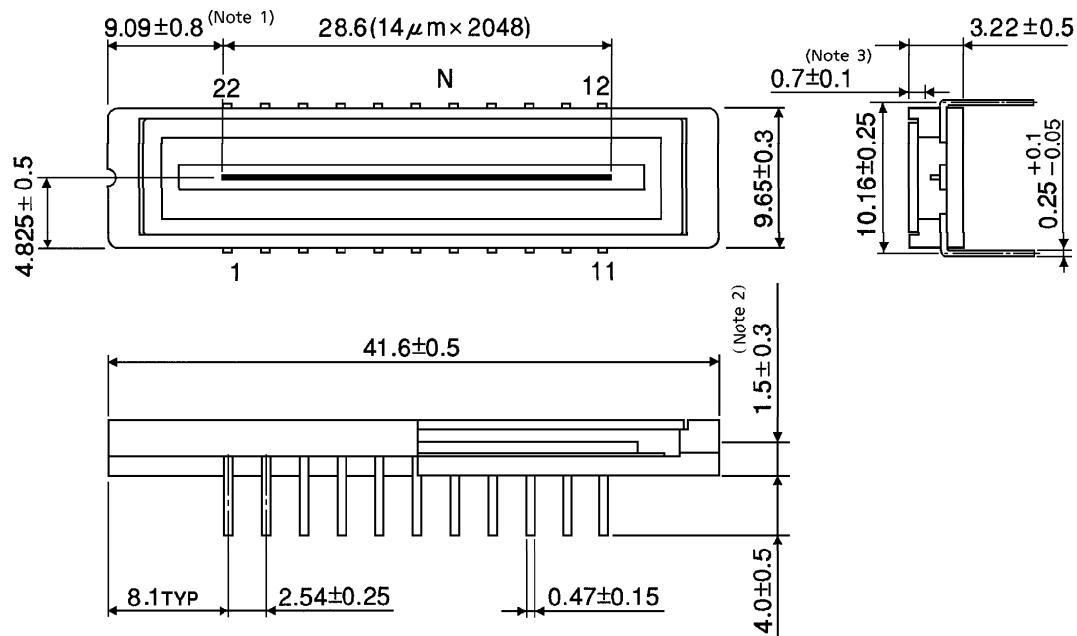
3. Incident Light

CCD image sensor has sensitivity in a wide range zone of light wave length, but its characteristics will sometimes widely change when used with long wave length input light outside the visual light zone.

OUTLINE DRAWING

WDIP22-G-400-2.54A (A)

Unit : mm



(Note 1) No. 1 SENSOR ELEMENT (S1) TO EDGE OF PACKAGE.

(Note 2) TOP OF CHIP TO BOTTOM OF PACKAGE.

(Note 3) GLASS THICKNES (n = 1.5)